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- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- True Logic Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), Standard Plastic (N) and Ceramic (J) 300-mil DIPs, and Ceramic Flat (W) Packages

description

These octal D-type transparent latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

While the latch-enable (LE) input is high, outputs (Q) respond to the data (D) inputs. When LE is low, the outputs are latched to retain the data that was set up.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

 \overline{OE} does not affect internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS573C and SN54AS573A are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS573C and SN74AS573A are characterized for operation from 0°C to 70°C.

(each latch)										
	INPUTS	OUTPUT								
OE	LE	D	Q							
L	Н	Н	Н							
L	н	L	L							
L	L	Х	Q ₀							
н	Х	Х	Z							

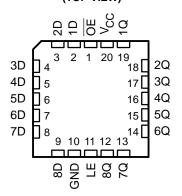
FUNCTION TABLE

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

SN54ALS5/3C, SN54AS5/3A J OR W PACKAGE
SN74ALS573C, SN74AS573A DW OR N PACKAGE
(TOP VIEW)

	()								
OE		U] v _{cc}						
1D	2	19] 1Q						
2D	3	18] 2Q						
3D	4	17] 3Q						
4D	5	16] 4Q						
5D	6	15] 5Q						
6D	7	14] 6Q						
7D	8	13] 7Q						
8D	9	12] 8Q						
GND	10	11	LE						
	L								

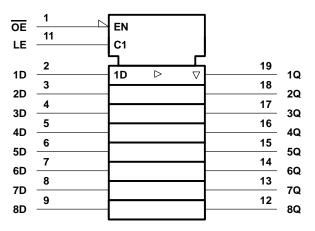
SN54ALS573C, SN54AS573A ... FK PACKAGE (TOP VIEW)



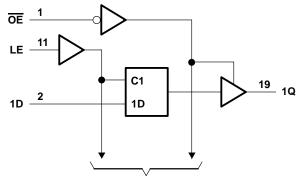
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logic symbol[†]



logic diagram (positive logic)



To Seven Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC}	
Input voltage, V _I	
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN54ALS573C	. −55°C to 125°C
SN74ALS573C	0°C to 70°C
Storage temperature range	. −65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS573C		SN74ALS573C			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
ЮН	High-level output current			-1			-2.6	mA
IOL	Low-level output current			12			24	mA
tw	Pulse duration, LE high	25			10			ns
t _{su}	Setup time, data before LE \downarrow	10			10			ns
t _h	Hold time, data after LE \downarrow	7			7			ns
TA	Operating free-air temperature	-55		125	0		70	°C



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PARAMETER	TEST	TEST CONDITIONS		SN54ALS573C			4ALS57	'3C	UNIT
PARAMETER	TEST C			TYP†	MAX	MIN	TYP†	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lj = -18 mA			-1.2			-1.2	V
	V_{CC} = 4.5 V to 5.5 V,	I _{OH} = -0.4 mA	V _{CC} -2			V _{CC} -2			
VOH	V _{CC} = 4.5 V	I _{OH} = -1 mA	2.4	3.3					V
	$v_{\rm CC} = 4.5 v$	I _{OH} = -2.6 mA				2.4	3.2		
Ve	VCC = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	v
VOL	VCC = 4.5 V	I _{OL} = 24 mA					0.35	0.5	v
IOZH	V _{CC} = 5.5 V,	V _O = 2.7 V			20			20	μA
lozl	V _{CC} = 5.5 V,	V _O = 0.4 V			-20			-20	μA
lj –	$V_{CC} = 5.5 V,$	V _I = 7 V			0.1			0.1	mA
ΙН	$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μA
١ _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.13			-0.1	mA
10‡	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
		Outputs high		10	17		10	17	
ICC	$V_{CC} = 5.5 V$	Outputs low		15	24		15	24	mA
		Outputs disabled		16	27		16	27	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 4.5 V \text{ to } 5.5 V,$ $C_L = 50 \text{ pF},$ $R1 = 500 \Omega,$ $R2 = 500 \Omega,$ $T_A = \text{MIN to MAX}$		UNIT		
			SN54AL	S573C	SN74AL	S573C	
		MIN	MAX	MIN	MAX		
^t PLH	D	•	2	20	2	14	ns
^t PHL		Q	2	17	2	14	115
^t PLH	. –	<u> </u>	8	33	6	20	
^t PHL	LE	Q	8	24	6	19	ns
^t PZH			4	28	3	18	
tPZL	OE	Q	4	21	4	18	ns
^t PHZ	OE	0	2	20	1	10	
^t PLZ	UE	Q	3	26	1	15	ns

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC}	
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN54AS573A	−55°C to 125°C
SN74AS573A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54AS573A		SN74AS573A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-12			-15	mA
IOL	Low-level output current			32			48	mA
tw*	Pulse duration, LE high	5.5			4.5			ns
t _{su} *	Setup time, data before LE \downarrow	2			2			ns
t _h *	Hold time, data after LE \downarrow	3			3			ns
Т _А	Operating free-air temperature	-55		125	0		70	°C

* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST	TEST CONDITIONS SN54AS573A SN74AS573A			SN54AS573A		BA	UNIT	
PARAMETER	TEST C	TEST CONDITIONS		түр‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lı = –18 mA			-1.2			-1.2	V
	V_{CC} = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		
VOH	V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2.4	3.2					V
	VCC = 4.3 V	$I_{OH} = -15 \text{ mA}$				2.4	3.3		
Ve	$V_{CC} = 4.5 V$	I _{OL} = 32 mA		0.28	0.5				V
VOL		I _{OL} = 48 mA					0.33	0.5	v
IOZH	$V_{CC} = 5.5 V,$	V _O = 2.7 V			50			50	μΑ
I _{OZL}	$V_{CC} = 5.5 V,$	V _O = 0.4 V			-50			-50	μΑ
lj	V _{CC} = 5.5 V,	VI = 7 V			0.1			0.1	mA
Ιн	V _{CC} = 5.5 V,	VI = 2.7 V			20			20	μA
١ _{١L}	V _{CC} = 5.5 V,	VI = 0.4 V			-0.1			-0.5	mA
١ _O §	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
		Outputs high		56	93		56	93	
ICC	V _{CC} = 5.5 V	Outputs low		55	90		55	90	mA
		Outputs disabled		65	106		65	106	

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

\$ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



SN54ALS573C, SN54AS573A, SN74ALS573C, SN74AS573A **OCTAL D-TYPE TRANSPARENT LATCHES** WITH 3-STATE OUTPUTS SDAS048D – DECEMBER 1989 – REVISED JANUARY 1995

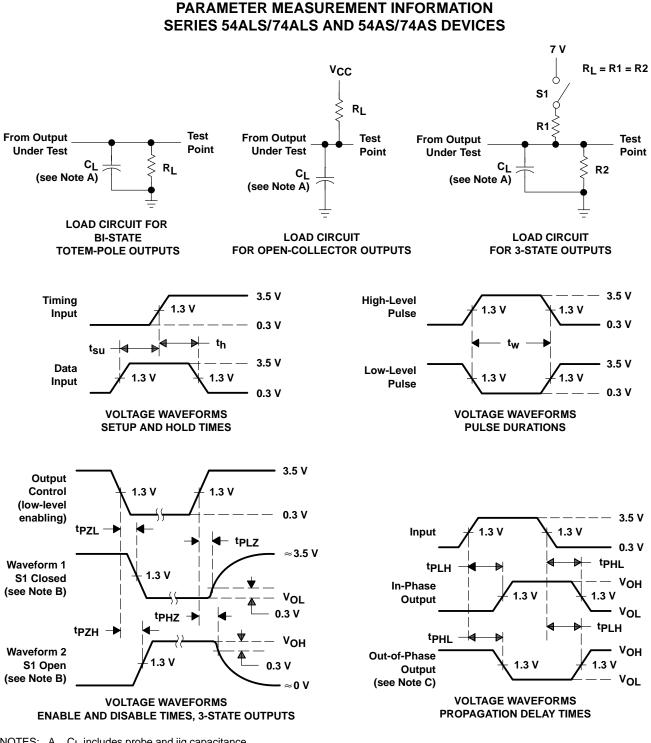
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	CI R1 R2	CC = 4.5 _ = 50 pF I = 500 Ω 2 = 500 Ω A = MIN t	2, 2,	;	UNIT
			SN54AS	6573A	SN74AS573A		
			MIN	MAX	MIN	MAX	
^t PLH	D	•	3	11	3	8	ns
^t PHL	U	Q	3	8	3	7	115
^t PLH	LE	0	6	16.5	6	13	ns
^t PHL	LL	Q	4	9	4	7.5	115
^t PZH	OE		2	8	2	6.5	20
^t PZL	ÜE	Q	4	11	4	9.5	ns
^t PHZ	OE	0	2	8	2	6.5	
^t PLZ	UE	Q	2	8	2	7	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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